

ACL Products

FEATURES

- Output capability: ± 24 mA
- CMOS (AC) and TTL (ACT) voltage level inputs
- 50 Ω Incident wave switching
- Center-pin V_{CC} and ground configuration to minimize high-speed switching noise
- I_{CC} category: MSI

DESCRIPTION

The 74AC/ACT11174 high-performance CMOS devices combine very high speed and high output drive comparable to the most advanced TTL families.

The 74AC/ACT11174 provides six D-type flip-flops with independent Data inputs, shared Clock and Master Reset inputs, and Q outputs.

Master Reset ($\overline{MR}$) is an asynchronous active-Low input and operates independently of the Clock input. Information on the Data (D) input is transferred to the Q output on the Low-to-High transition of the clock pulse. Clock triggering is threshold voltage dependent. The D inputs must be stable one set-up time prior to the Low-to-High clock transition for predictable operation.

GENERAL INFORMATION

SYMBOL	PARAMETER	CONDITIONS $T_A = 25^\circ\text{C}; \text{GND} = 0\text{V}$ $V_{CC} = 5.0\text{V}$	TYPICAL		UNIT
			AC	ACT	
t_{PLH}/t_{PHL}	Propagation delay CP to Q_n	$C_L = 50\text{pF}$	4.4	5.5	ns
C_{PD}	Power dissipation capacitance per flip-flop ¹	$f = 1\text{MHz}; C_L = 50\text{pF}$	31	30	pF
C_{IN}	Input capacitance	$V_I = 0\text{V}$ or V_{CC}	4.0	4.0	pF
I_{LATCH}	Latch-up current	Per Jeduc JC40.2 Standard 17	500	500	mA
f_{MAX}	Maximum clock frequency	$C_L = 50\text{pF}$	160	150	MHz

Note:

1. C_{PD} is used to determine the dynamic power dissipation (P_D in μW):

$$P_D = C_{PD} \times V_{CC}^2 \times f_I + \sum (C_L \times V_{CC}^2 \times f_O) \text{ where:}$$

f_I = input frequency in MHz, C_L = output load capacitance in pF,

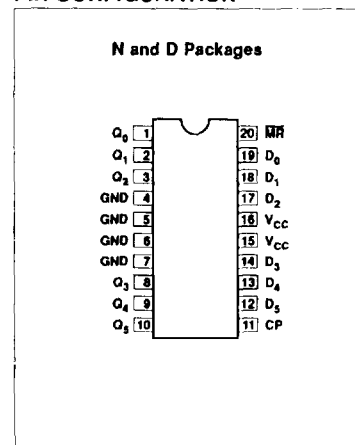
f_O = output frequency in MHz, V_{CC} = supply voltage in V,

$\sum (C_L \times V_{CC}^2 \times f_O)$ = sum of outputs

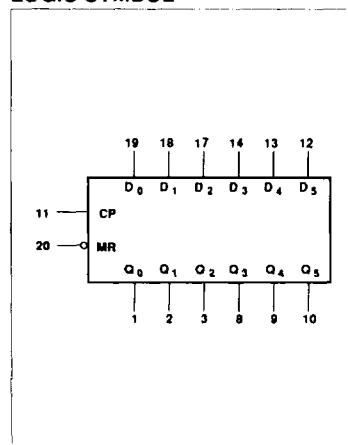
ORDERING INFORMATION

PACKAGES	TEMPERATURE RANGE	ORDER CODE
20-pin plastic DIP (300mil-wide)	-40°C to +85°C	74AC11174N 74ACT11174N
20-pin plastic SO (300mil-wide)	-40°C to +85°C	74AC11174D 74ACT11174D

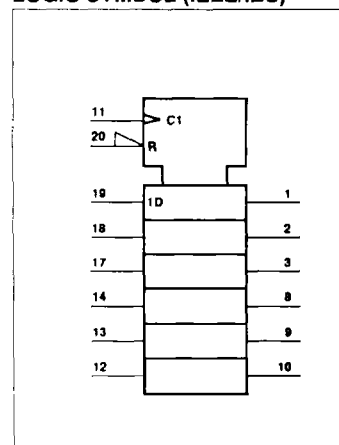
PIN CONFIGURATION



LOGIC SYMBOL



LOGIC SYMBOL (IEEE/IEC)



Hex D-Type Flip-Flop w/Reset;
Positive-Edge Trigger

74AC/ACT11174

PIN DESCRIPTION

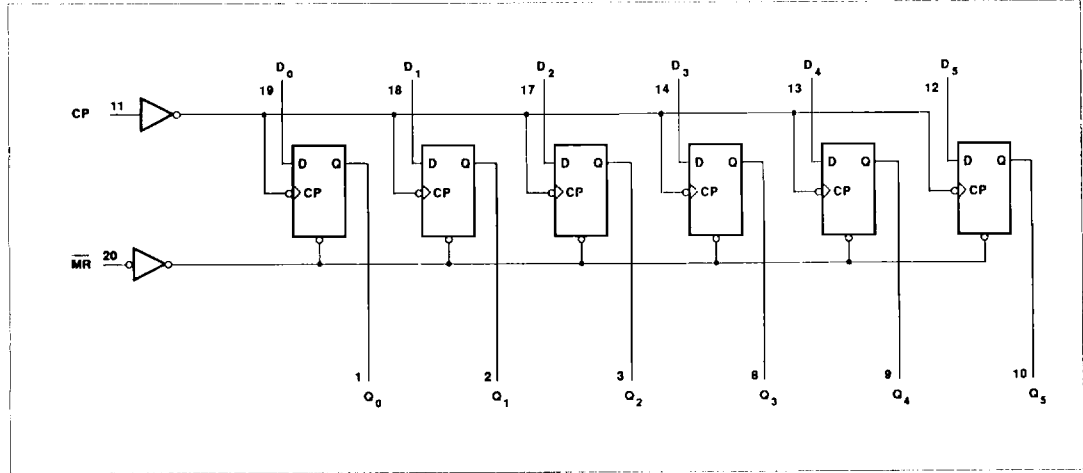
PIN NUMBER	SYMBOL	NAME AND FUNCTION
19, 18, 17, 14, 13, 12	$D_0 - D_5$	Data inputs
1, 2, 3, 8, 9, 10	$Q_0 - Q_5$	Data outputs
20	$\overline{MR}$	Master reset input (active Low)
11	CP	Clock input
4, 5, 6, 7	GND	Ground (0V)
15, 16	V_{CC}	Positive supply voltage

FUNCTION TABLE

OPERATING MODE	INPUTS			OUTPUTS
	$\overline{MR}$	CP	D_n	Q_n
Asynchronous reset	L	X	X	L
Load "1" (set)	H	$\uparrow$	h	H
Load "0" (reset)	H	$\uparrow$	l	L

H = High voltage level steady state
h = High voltage level one set-up time prior to the Low-to-High clock transition
L = Low voltage level steady state
l = Low voltage level one set-up time prior to the Low-to-High clock transition
X = Don't care
 $\uparrow$ = Low-to-High clock transition

LOGIC DIAGRAM



Hex D-Type Flip-Flop w/Reset; Positive-Edge Trigger

74AC/ACT11174

RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	74AC11174			74ACT11174			UNIT
		Min	Nom	Max	Min	Nom	Max	
V_{CC}	DC supply voltage	3.0 ¹	5.0	5.5	4.5	5.0	5.5	V
V_I	Input voltage	0		V_{CC}	0		V_{CC}	V
V_O	Output voltage	0		V_{CC}	0		V_{CC}	V
$\Delta V/\Delta v$	Input transition rise or fall rate	0		10	0		10	ns/V
T_A	Operating free-air temperature	-40		+85	-40		+85	°C

NOTE:

1. No electrical or switching characteristics are specified at $V_{CC} < 3V$. Operation between 2V and 3V is not recommended, but within that range, a device output will maintain a previously established logic state.

ABSOLUTE MAXIMUM RATINGS¹

SYMBOL	PARAMETER	TEST CONDITIONS	RATING	UNIT
V_{CC}	DC supply voltage		-0.5 to +7.0	V
I_{IK} or V_I	DC input diode current ²	$V_I < 0$	-20	mA
		$V_I > V_{CC}$	20	
	DC input voltage		-0.5 to $V_{CC} + 0.5$	V
I_{OK} or V_O	DC output diode current ²	$V_O < 0$	-50	mA
		$V_O > V_{CC}$	50	
	DC output voltage		-0.5 to $V_{CC} + 0.5$	V
I_O	DC output source or sink current per output pin	$V_O = 0$ to V_{CC}	±50	mA
I_{CC} or I_{GND}	DC V_{CC} current		±150	mA
	DC ground current		±150	
T_{STG}	Storage temperature		-65 to 150	°C
P_{TOT}	Power dissipation per package Plastic DIP	Above 70°C: derate linearly by 8mW/K	500	mW
	Power dissipation per package Plastic surface mount (SO)	Above 70°C: derate linearly by 6mW/K	400	mW

NOTES:

1. Stresses beyond those listed may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
2. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

Hex D-Type Flip-Flop w/Reset; Positive-Edge Trigger

74AC/ACT11174

DC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS	V _{CC} V	74AC11174				74ACT11174				UNIT
				T _A = +25°C		T _A = -40°C to +85°C		T _A = +25°C		T _A = -40°C to +85°C		
				Min	Max	Min	Max	Min	Max	Min	Max	
V _{IH}	High-level input voltage		3.0	2.10		2.10						V
			4.5	3.15		3.15		2.0		2.0		
			5.5	3.85		3.85		2.0		2.0		
V _{IL}	Low-level input voltage		3.0		0.90		0.90					V
			4.5		1.35		1.35		0.8		0.8	
			5.5		1.65		1.65		0.8		0.8	
V _{OH}	High-level output voltage	V _I = V _{IL} or V _{IH}	I _{OH} = -50μA	3.0	2.9		2.9					V
				4.5	4.4		4.4		4.4		4.4	
				5.5	5.4		5.4		5.4		5.4	
			I _{OH} = -4mA	3.0	2.58		2.48					
				4.5	3.94		3.8		3.94		3.8	
			I _{OH} = -24mA	5.5	4.94		4.8		4.94		4.8	
				5.5			3.85				3.85	
V _{OL}	Low-level output voltage	V _I = V _{IL} or V _{IH}	I _{OL} = 50μA	3.0		0.1	0.1					V
				4.5		0.1	0.1		0.1		0.1	
				5.5		0.1	0.1		0.1		0.1	
			I _{OL} = 12mA	3.0	0.36		0.44					
				4.5	0.36		0.44		0.36		0.44	
			I _{OL} = 24mA	5.5	0.36		0.44		0.36		0.44	
				5.5			1.65				1.65	
I _I	Input leakage current	V _I = V _{CC} or GND	5.5		±0.1		±1.0		±0.1		±1.0	μA
I _{CC}	Quiescent supply current	V _I = V _{CC} or GND, I _O = 0	5.5		8.0		80		8.0		80	μA
ΔI _{CC}	Supply current, TTL inputs High ²	One input at 3.4V, other inputs at V _{CC} or GND	5.5						0.9		1.0	mA

NOTES:

1. Not more than one output should be tested at a time, and the duration of the test should not exceed 10ms.

2. This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0V or V_{CC}.